

**Search Notes**

Application/Control No.

10/602,629

Examiner

John D. Lee

Applicant(s)/Patent under  
Reexamination

WATANABE, SHIGEKI

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
359	326-332	2/24/2005	JDL
359	107,108	2/24/2005	JDL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO "WEST" Database searched; search strategy on separate sheet.	2/24/2005	JDL